



VNQ05XSP16

QUAD CHANNEL HIGH SIDE SOLID STATE RELAY

| TYPE | R _{ON} (*) | I _{OUT} | V _{CC} |
|------------|---------------------|------------------|-----------------|
| VNQ05XSP16 | 110mΩ | 5A (*) | 36 V |

(*) Per each channel

- OUTPUT CURRENT (CONTINUOUS): 5A
- CMOS COMPATIBLE INPUTS
- MULTIPLEXED PROPORTIONAL LOAD CURRENT SENSE
- UNDERVOLTAGE & OVERVOLTAGE SHUT-DOWN
- OVERVOLTAGE CLAMP
- THERMAL SHUT DOWN
- CURRENT LIMITATION
- VERY LOW STAND-BY POWER DISSIPATION
- PROTECTION AGAINST:
 - LOSS OF GROUND & LOSS OF V_{CC}
- REVERSE BATTERY PROTECTION (**)

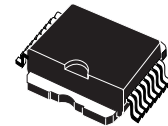
DESCRIPTION

The VNQ05XSP16 is a monolithic device designed in STMicroelectronics VIPower M0-3

ABSOLUTE MAXIMUM RATING

| Symbol | Parameter | Value | Unit |
|---------------------|---|--------------------|--------|
| V _{CC} | Supply voltage (continuous) | 41 | V |
| -V _{CC} | Reverse supply voltage (continuous) | -0.3 | V |
| I _{OUT} | Output current (continuous), for each channel | Internally limited | A |
| I _R | Reverse output current (continuous), for each channel | -5 | A |
| I _{IN} | Input current (IN1, IN2, IN3, IN4, SELA, SELB, SENSENABLE) | +/- 10 | mA |
| V _{CSENSE} | Current sense maximum voltage | -3 +15 | V V |
| I _{GND} | Ground current at T _{case} ≤ 25°C (continuous) | -200 | mA |
| V _{ESD} | Electrostatic Discharge (Human Body Model: R=1.5Ω; C=100pF) | | |
| | - INPUT | 4000 | V |
| | - CURRENT SENSE | 2000 | V |
| | - OUTPUT | 5000 | V |
| | - V _{CC} | 5000 | V |
| P _{tot} | Power dissipation at T _{case} =25°C | 78 | W |
| E _{MAX} | Maximum Switching Energy (L=1.72mH; R _L =0Ω; V _{bat} =13.5V; T _{jstart} =150°C; I _L =7.5A) | 76 | mJ |
| T _j | Junction operating temperature | Internally limited | °C |
| T _c | Case Operating Temperature | - 40 to 150 | °C |
| T _{STG} | Storage temperature | -55 to 150 | °C |

(**) See application schematic at page 9



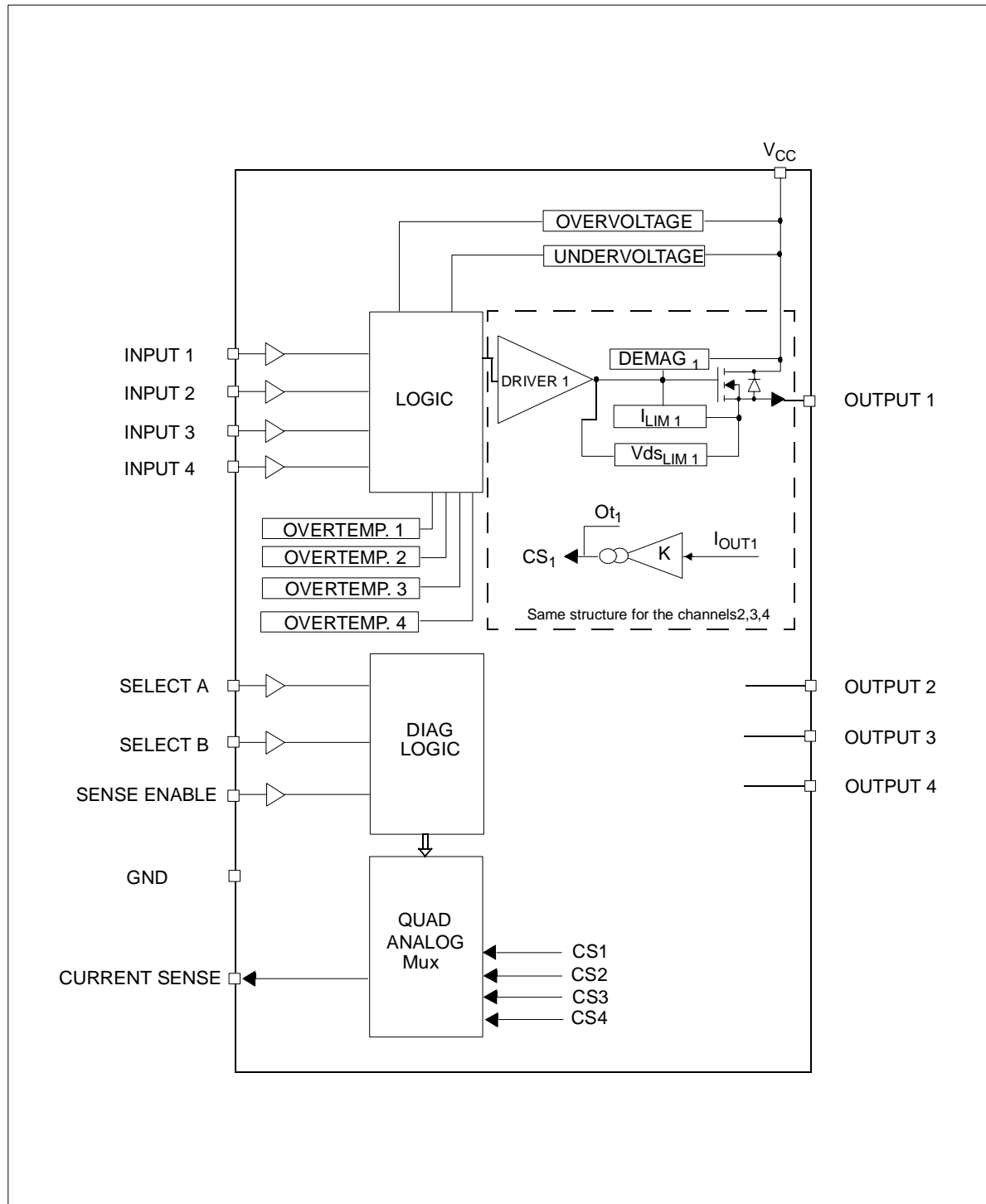
PowerSO-16™

ORDER CODES

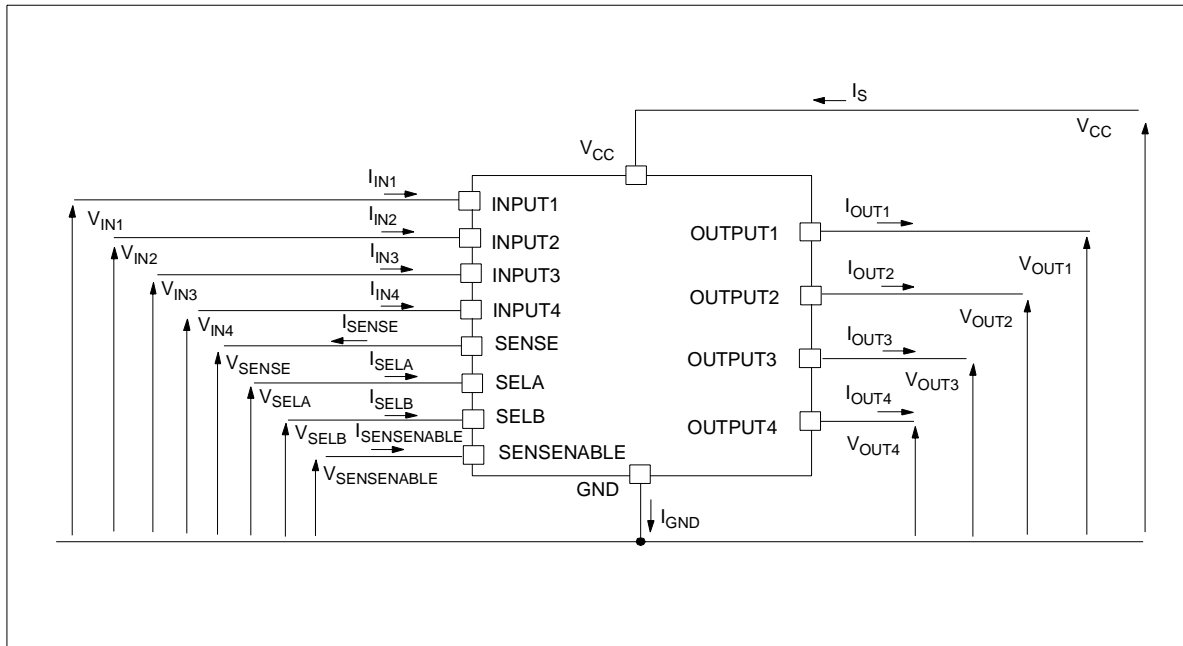
| PACKAGE | TUBE | T&R |
|-------------|------------|----------------|
| PowerSO-16™ | VNQ05XSP16 | VNQ05XSP1613TR |

Technology. It is intended for driving any type of multiple loads with one side connected to ground. Active V_{CC} pin voltage clamp protects the device against low energy spikes (see ISO7637 transient compatibility table). This device has four independent channels and one multiplexed analog sense output which deliver a current proportional to the selected output current. SenseEnable pin allows to connect any number of VNQ05XSP16 on the same Current Sense line. Active current limitation combined with thermal shut-down and automatic restart protect the device against overload. Device automatically turns off in case of ground pin disconnection.

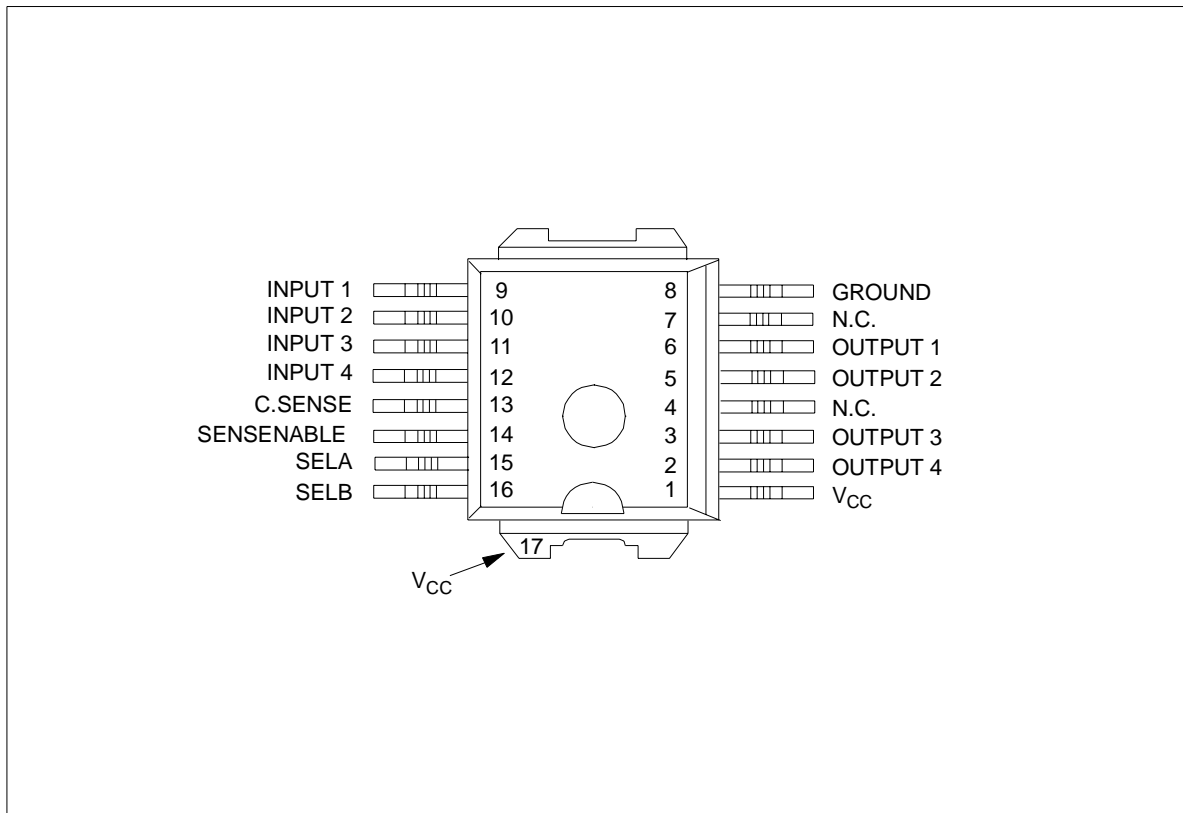
BLOCK DIAGRAM



CURRENT AND VOLTAGE CONVENTIONS



CONNECTION DIAGRAM (TOP VIEW)



VNQ05XSP16

THERMAL DATA

| Symbol | Parameter | Value | Unit |
|----------------|---|----------|------|
| $R_{thj-case}$ | Thermal resistance junction-case (MAX) | 1.6 | °C/W |
| $R_{thj-amb}$ | Thermal resistance junction-ambient (MAX) | 51.6 (*) | °C/W |

(*) When mounted on FR4 printed circuit board with 0.5 cm² of copper area (at least 35 μm thick) connected to all V_{CC} pins

ELECTRICAL CHARACTERISTICS (8V < V_{CC} < 36V; -40°C < T_j < 150°C; unless otherwise specified) (Per each channel)

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Unit |
|----------------------|--------------------------|---|-----|-----|-------------------|----------|
| V _{CC} | Operating supply voltage | | 5.5 | 13 | 36 | V |
| V _{USD} | Under voltage shut down | | 3 | 4 | 5.5 | V |
| V _{OV} | Overvoltage shut down | | 36 | | | V |
| R _{ON} | On state resistance | I _{OUT1,2,3,4} =1A; T _j =25°C I _{OUT1,2,3,4} =1A; T _j =150°C I _{OUT1,2,3,4} =0.5A; V _{CC} =6V | | | 110 220 330 | mΩ |
| V _{clamp} | Clamp Voltage | I _{CC} =20mA (See note 1) | 41 | 48 | 55 | V |
| I _S | Supply current | Off state; Inputs=n.c.; V _{CC} =13V On state; V _{IN} =5V; V _{CC} =13V; I _{OUT} =0A; R _{SENSE} =3.9kΩ | | | 80 10 | μA mA |
| I _{L(off1)} | Off State Output Current | V _{IN} =V _{OUT} =0V | 0 | | 50 | μA |
| I _{L(off2)} | Off State Output Current | V _{IN} =0V; V _{OUT} =3.5V | -75 | | 0 | μA |
| I _{L(off3)} | Off State Output Current | V _{IN} =V _{OUT} =0V; V _{CC} =13V; T _j =125°C | | | 5 | μA |
| I _{L(off4)} | Off State Output Current | V _{IN} =V _{OUT} =0V; V _{CC} =13V; T _j =25°C | | | 3 | μA |

SWITCHING (V_{CC}=13V)

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Unit |
|--|------------------------|--|-----|----------------------|-----|------|
| t _{d(on)} | Turn-on delay time | R _L =2.6Ω channels 1,2,3,4 (see figure 2) | | 40 | | μs |
| t _{d(off)} | Turn-off delay time | R _L =2.6Ω channels 1,2,3,4 (see figure 2) | | 40 | | μs |
| (dV _{OUT} /dt) _{on} | Turn-on voltage slope | R _L =2.6Ω channels 1,2,3,4 (see figure 2) | | See relative diagram | | V/μs |
| (dV _{OUT} /dt) _{off} | Turn-off voltage slope | R _L =2.6Ω channels 1,2,3,4 (see figure 2) | | See relative diagram | | V/μs |

PROTECTIONS

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Unit |
|--------------------|--------------------------------|--|---------------------|---------------------|---------------------|--------|
| I _{lim} | DC short circuit current | V _{CC} =13V 5.5V < V _{CC} < 36V | 5 | 7.5 | 10 10 | A A |
| T _{TSD} | Thermal shut down temperature | | 150 | 175 | 200 | °C |
| T _R | Thermal reset temperature | | 135 | | | °C |
| T _{HYST} | Thermal hysteresis | | 7 | 15 | | °C |
| V _{demag} | Turn-off output voltage clamp | I _{OUT} =2A; L=6mH | V _{CC} -41 | V _{CC} -48 | V _{CC} -55 | V |
| V _{ON} | Output voltage drop limitation | I _{OUT} =0.1A T _j =-40°C...+150°C | | 50 | | mV |

Note 1: V_{clamp} and V_{OV} are correlated. Typical difference is 5V.

CURRENT SENSE ($9V < V_{CC} < 16V$)

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Unit |
|--------------------|--|--|-----|------|------|----------|
| K_1 | I_{OUT}/I_{SENSE} | $I_{OUT1,2} = 0.1A$; $V_{SENSE} = 0.5V$ $T_j = -40...+150^{\circ}C$ | 800 | 1000 | 1200 | |
| dK_1/K_1 | Current Sense Ratio Drift | $I_{OUT} = 0.1A$; $V_{SENSE} = 0.5V$; $T_j = -40^{\circ}C...+150^{\circ}C$ | -10 | | +10 | % |
| K_2 | I_{OUT}/I_{SENSE} | $I_{OUT1,2} = 1.0A$, $V_{SENSE} = 4V$ $T_j = -40...+150^{\circ}C$ | 800 | 1000 | 1200 | |
| dK_2/K_2 | Current Sense Ratio Drift | $I_{OUT} = 1.0A$; $V_{SENSE} = 4V$; $T_j = -40^{\circ}C...+150^{\circ}C$ | -8 | | +8 | % |
| K_3 | I_{OUT}/I_{SENSE} | $I_{OUT1,2} = 2.0A$, $V_{SENSE} = 4V$ $T_j = -40...+150^{\circ}C$ | 850 | 1000 | 1150 | |
| dK_3/K_3 | Current Sense Ratio Drift | $I_{OUT} = 2.0A$; $V_{SENSE} = 4V$; $T_j = -40^{\circ}C...+150^{\circ}C$ | -6 | | +6 | % |
| I_{SENSE0} | Analog Sense Leakage Current | $V_{CC} = 6...16V$; $I_{OUT} = 0A$; $V_{SENSE} = 0V$; $T_j = -40^{\circ}C...+150^{\circ}C$ | 0 | | 10 | μA |
| $V_{SENSE1,2,3,4}$ | Max analog sense output voltage | $V_{CC} = 5.5V$, $I_{OUT1,2,3,4} = 1.0A$ $R_{SENSE} = 10k\Omega$ $V_{CC} > 8V$, $I_{OUT1,2,3,4} = 2.0A$ $R_{SENSE} = 10k\Omega$ | 2 | | | V |
| V_{SENSEH} | Analog sense output voltage in overtemperature condition | $V_{CC} = 13V$; $R_{SENSE} = 3.9k\Omega$ | | 5.5 | | V |
| $R_{VSENSEH}$ | Analog sense output impedance in overtemperature condition | $V_{CC} = 13V$; $T_j > T_{TSD}$; All Channels Open | | 400 | | Ω |
| t_{DSENSE} | Current sense delay | $V_{CC} = 13V$; $R_{SENSE} = 3.9k\Omega$ (see note 2) | | 300 | 500 | μs |

LOGIC CHARACTERISTICS (Inputs, Sela&b, Sensenable)

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Unit |
|---------------|--------------------------|-----------------------------------|------|-------------|------|---------|
| V_{IL} | Input low level voltage | | | | 1.25 | V |
| V_{IH} | Input high level voltage | | 3.25 | | | V |
| $V_{I(hyst)}$ | Input hysteresis voltage | | 0.5 | | | V |
| I_{IL} | Low level input current | $V_{IN} = 1.25V$ | 1 | | | μA |
| I_{IN} | High level input current | $V_{IN} = 3.25V$ | | | 10 | μA |
| V_{ICL} | Input clamp voltage | $I_{IN} = 1mA$ $I_{IN} = -1mA$ | 6 | 6.8 -0.7 | 8 | V |

Note 2: current sense signal delay after positive input slope.

Note: Sense pin doesn't have to be left floating.

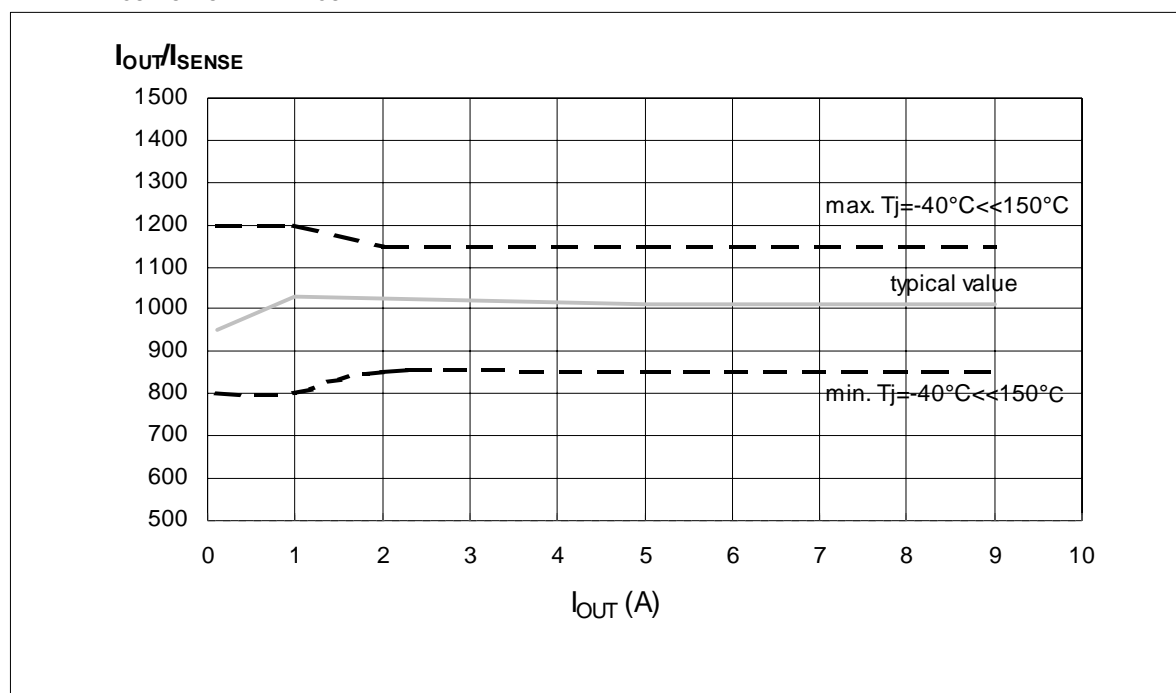
TRUTH TABLE

| CONDITIONS | INPUT | OUTPUT | SENSE |
|-------------------------------|-------|--------|--------------------------------|
| Normal operation | L | L | 0 |
| | H | H | Nominal |
| Overtemperature | L | L | 0 |
| | H | L | V_{SENSEH} |
| Undervoltage | L | L | 0 |
| | H | L | 0 |
| Overvoltage | L | L | 0 |
| | H | L | 0 |
| Short circuit to GND | L | L | 0 |
| | H | L | $(T_j < T_{TSD})$ 0 |
| | H | L | $(T_j > T_{TSD})$ V_{SENSEH} |
| Short circuit to V_{CC} | L | H | 0 |
| | H | H | < Nominal |
| Negative output voltage clamp | L | L | 0 |

TRUTH TABLE

| SENSEABLE | SELB | SELA | SENSE |
|-----------|------|------|--------------------------|
| L | X | X | High Impedance |
| H | L | L | $I_{SENSE} = I_{OUT1}/K$ |
| H | L | H | $I_{SENSE} = I_{OUT2}/K$ |
| H | H | L | $I_{SENSE} = I_{OUT3}/K$ |
| H | H | H | $I_{SENSE} = I_{OUT4}/K$ |

Figure 1: I_{OUT}/I_{SENSE} versus I_{OUT}



ELECTRICAL TRANSIENT REQUIREMENTS

| ISO T/R 7637/1 Test Pulse | Test Levels I | Test Levels II | Test Levels III | Test Levels IV | Test Levels Delays and Impedance |
|---------------------------------|------------------|-------------------|--------------------|-------------------|-------------------------------------|
| 1 | -25V | -50V | -75V | -100V | 2ms, 10Ω |
| 2 | +25V | +50V | +75V | +100V | 0.2ms, 10Ω |
| 3a | -25V | -50V | -100V | -150V | 0.1μs, 50Ω |
| 3b | +25V | +50V | +75V | +100V | 0.1μs, 50Ω |
| 4 | -4V | -5V | -6V | -7V | 10ms, 0.01Ω |
| 5 | +26.5V | +46.5V | +66.5V | +86.5V | 400ms, 2Ω |

| ISO T/R 7637/1 Test Pulse | Test Levels Result I | Test Levels Result II | Test Levels Result III | Test Levels Result IV |
|---------------------------------|-------------------------|--------------------------|---------------------------|--------------------------|
| 1 | C | C | C | C |
| 2 | C | C | C | C |
| 3a | C | C | C | C |
| 3b | C | C | C | C |
| 4 | C | C | C | C |
| 5 | C | E | E | E |

| Class | Contents |
|-------|--|
| C | All functions of the device are performed as designed after exposure to disturbance. |
| E | One or more functions of the device is not performed as designed after exposure and cannot be returned to proper operation without replacing the device. |

Figure 2: Switching Characteristics (Resistive load $R_L=1.3\Omega$)

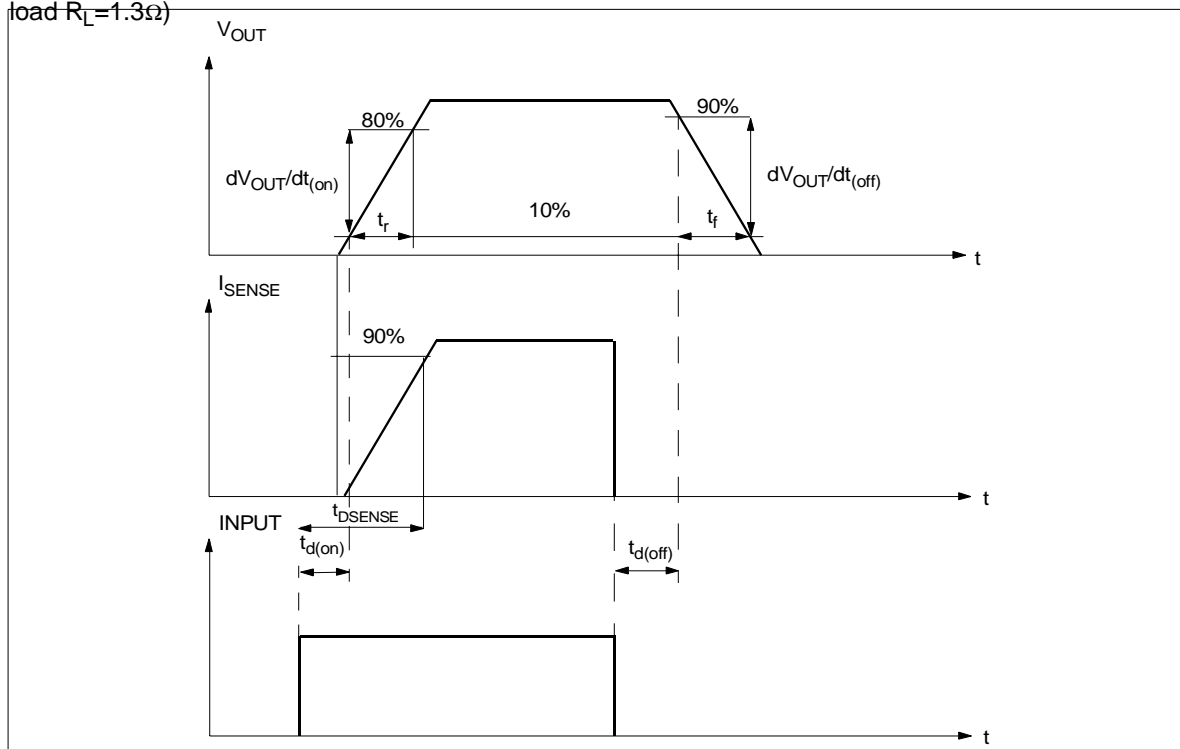
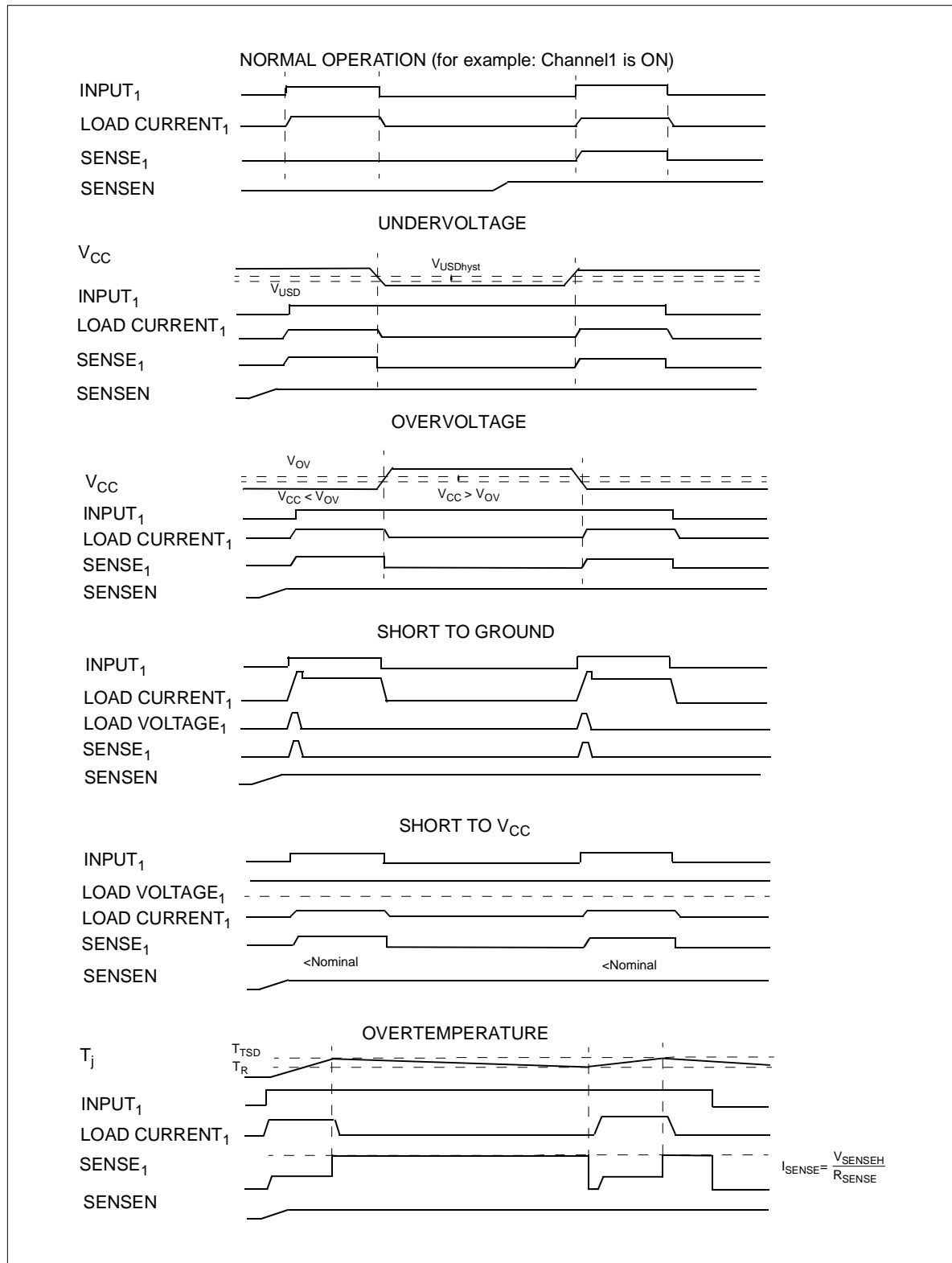
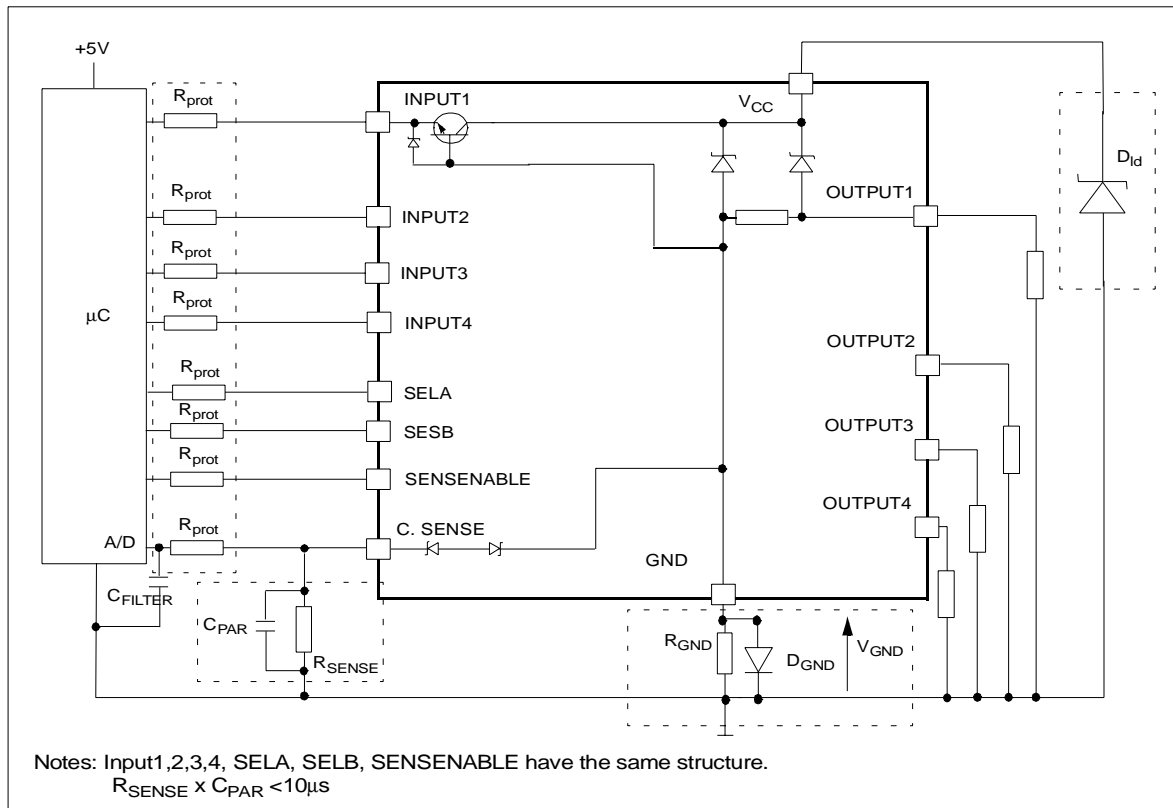


Figure 3: Waveforms



APPLICATION SCHEMATIC



GND PROTECTION NETWORK AGAINST REVERSE BATTERY

Solution 1: Resistor in the ground line (R_{GND} only). This can be used with any type of load.

The following is an indication on how to dimension the R_{GND} resistor.

- 1) $R_{GND} \leq 600mV / (I_{S(on)max})$.
- 2) $R_{GND} \geq (-V_{CC}) / (-I_{GND})$

where $-I_{GND}$ is the DC reverse ground pin current and can be found in the absolute maximum rating section of the device's datasheet.

Power Dissipation in R_{GND} (when $V_{CC} < 0$: during reverse battery situations) is:

$$P_D = (-V_{CC})^2 / R_{GND}$$

This resistor can be shared amongst several different HSD. Please note that the value of this resistor should be calculated with formula (1) where $I_{S(on)max}$ becomes the sum of the maximum on-state currents of the different devices.

Please note that if the microprocessor ground is not common with the device ground then the R_{GND} will produce a shift ($I_{S(on)max} \times R_{GND}$) in the input thresholds and the status output values. This shift will vary depending on how many devices are ON in the case of several high side drivers sharing the same R_{GND} .

If the calculated power dissipation leads to a large resistor or several devices have to share the same resistor then the ST suggests to utilize Solution 2 (see below).

Solution 2: A diode (D_{GND}) in the ground line.

A resistor ($R_{GND} = 1k\Omega$) should be inserted in parallel to D_{GND} if the device will be driving an inductive load.

This small signal diode can be safely shared amongst several different HSD. Also in this case, the presence of the ground network will produce a shift ($\approx 600mV$) in the input threshold and the status output values if the microprocessor ground is not common with the device ground. This shift will not vary if more than one HSD shares the same diode/resistor network.

LOAD DUMP PROTECTION

D_{Id} is necessary (Voltage Transient Suppressor) if the load dump peak voltage exceeds V_{CC} max DC rating. The same applies if the device will be subject to transients on the V_{CC} line that are greater than the ones shown in the ISO T/R 7637/1 table.

 μC I/Os PROTECTION:

If a ground protection network is used and negative transients are present on the V_{CC} line, the control pins will be pulled negative. ST suggests to insert a resistor (R_{prot}) in line to prevent the μC I/Os pins to latch-up.

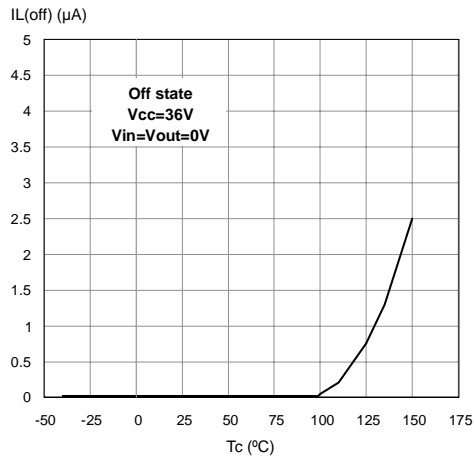
The value of these resistors is a compromise between the leakage current of μC and the current required by the HSD I/Os (Input levels compatibility) with the latch-up limit of μC I/Os.

$$-V_{CCpeak} / I_{latchup} \leq R_{prot} \leq (V_{OH\mu C} - V_{IH} - V_{GND}) / I_{IHmax}$$

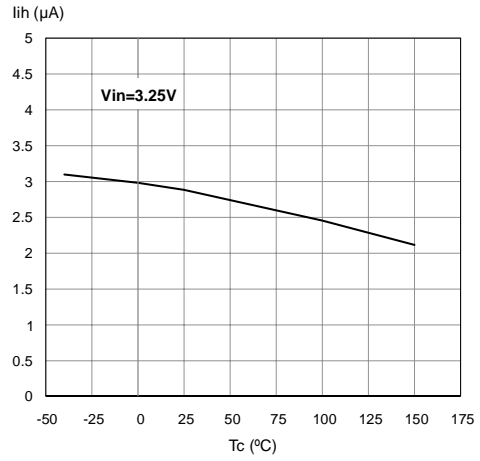
For $V_{CCpeak} = -100V$ and $I_{latchup} \geq 20mA$; $V_{OH\mu C} \geq 4.5V$
 $5k\Omega \leq R_{prot} \leq 65k\Omega$.

Recommended R_{prot} value is 10k Ω .

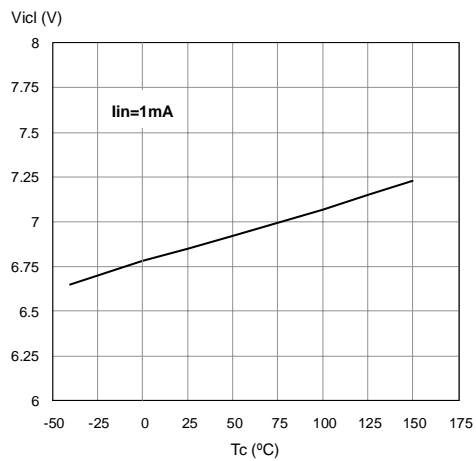
Off State Output Current



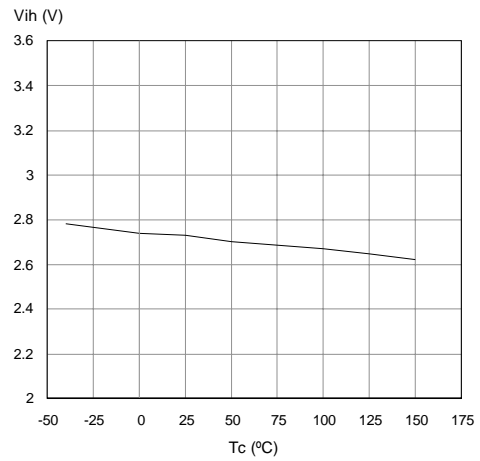
High Level Input Current



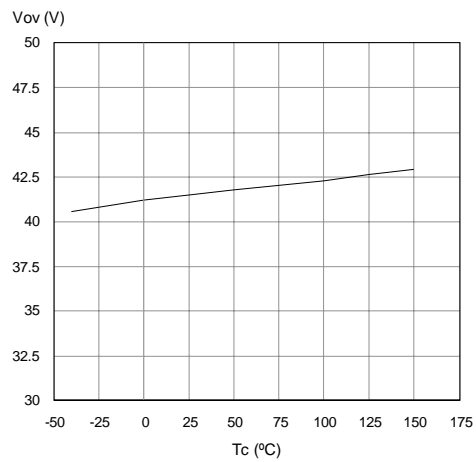
Input Clamp Voltage



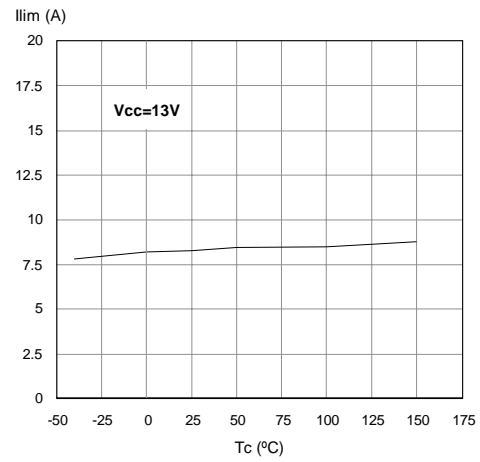
Input High Level



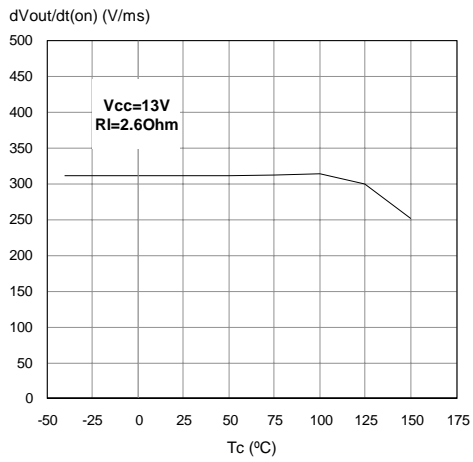
Overvoltage Shutdown



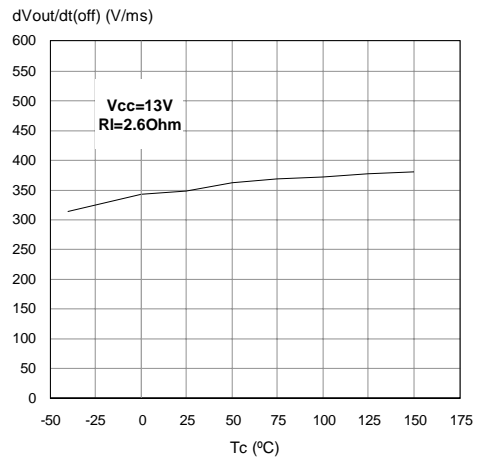
I_{LIM} Vs T_{case}



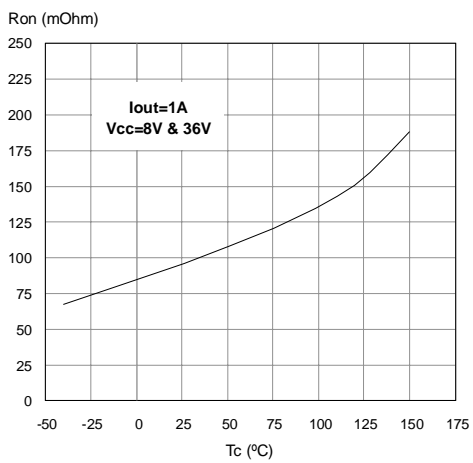
Turn-on Voltage Slope



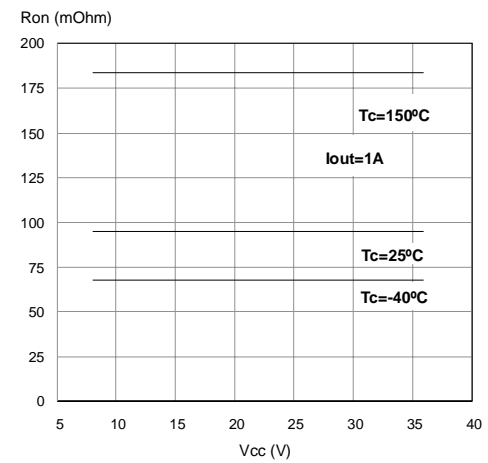
Turn-off Voltage Slope



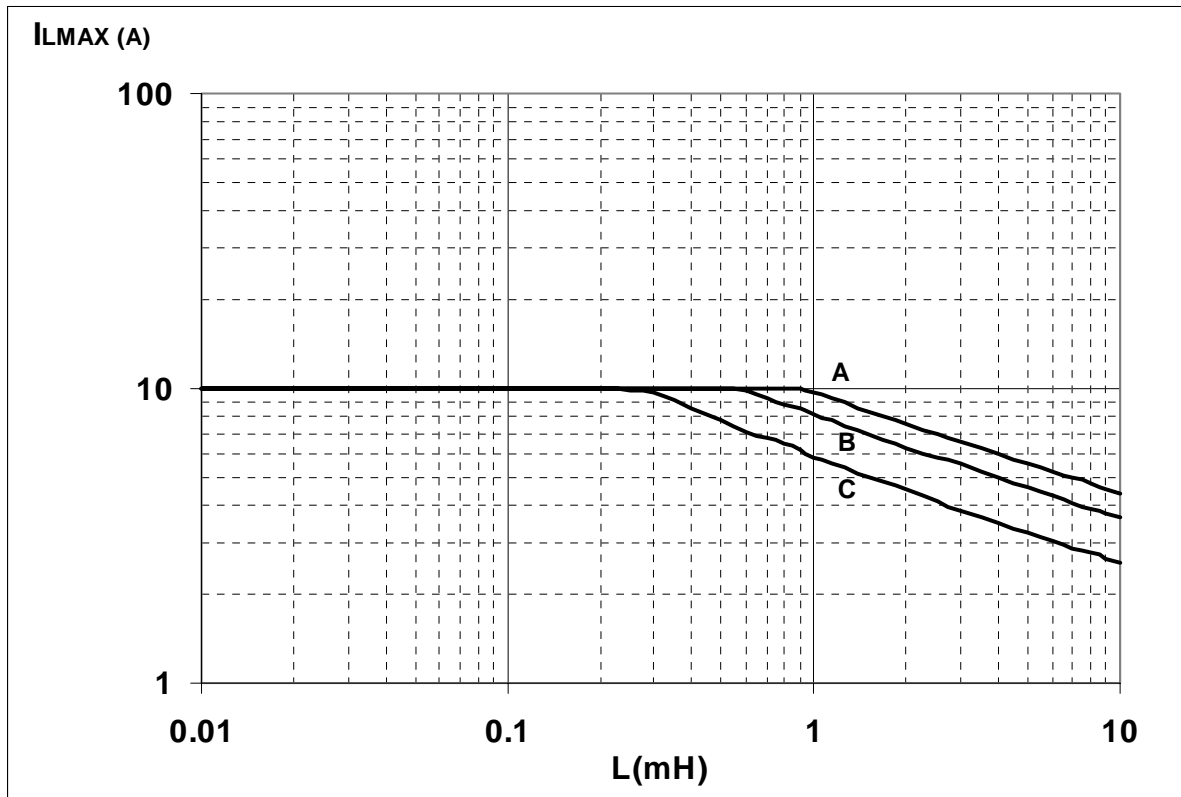
On State Resistance Vs T_{case}



On State Resistance Vs V_{CC}



Maximum turn off current versus load inductance



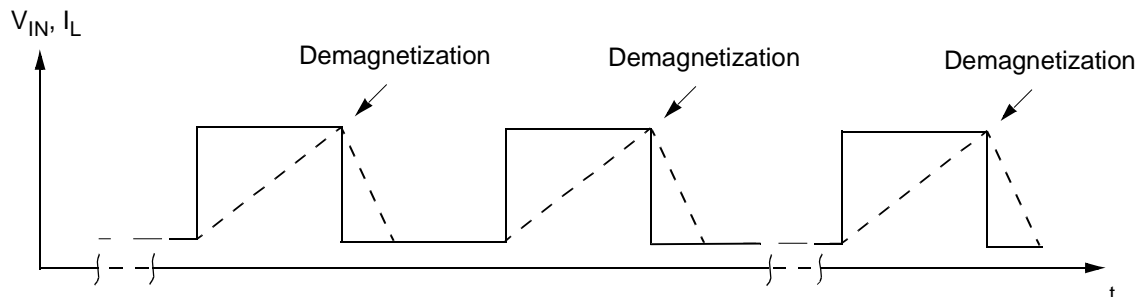
- A = Single Pulse at $T_{Jstart}=150^{\circ}C$
- B= Repetitive pulse at $T_{Jstart}=100^{\circ}C$
- C= Repetitive Pulse at $T_{Jstart}=125^{\circ}C$

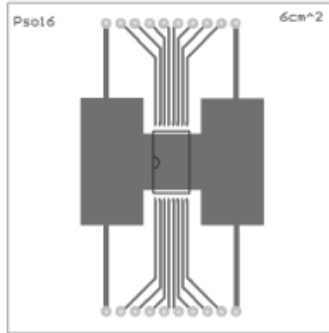
Conditions:

$V_{CC}=13.5V$

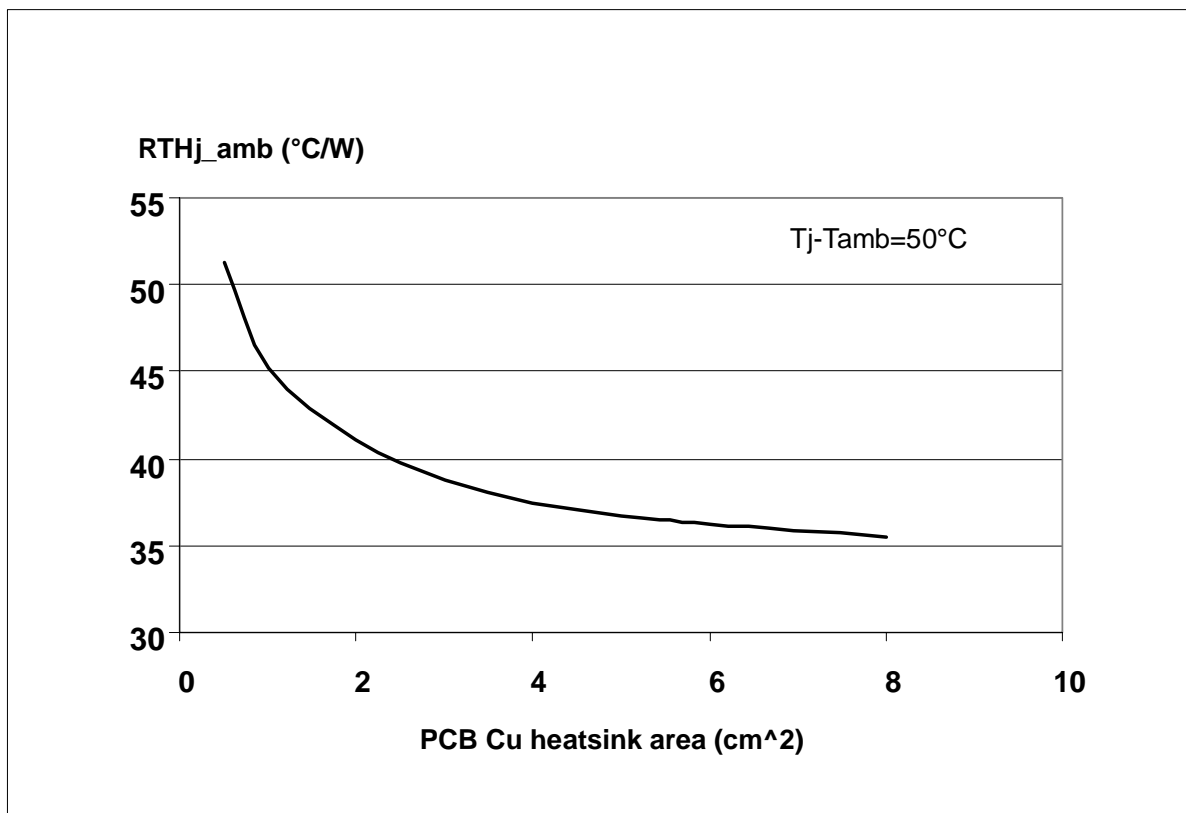
Values are generated with $R_L=0\Omega$

In case of repetitive pulses, T_{jstart} (at beginning of each demagnetization) of every pulse must not exceed the temperature specified above for curves B and C.

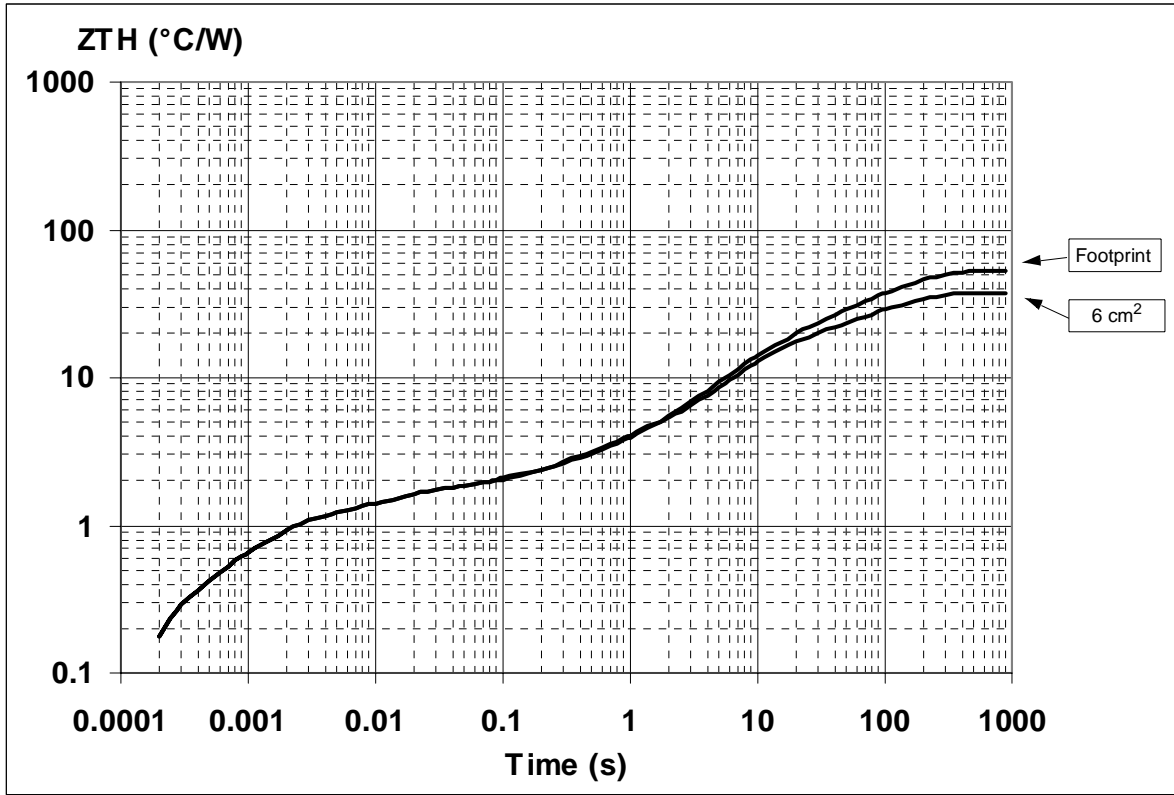


PowerSO-16™ THERMAL DATA**PowerSO-16™ PC Board**

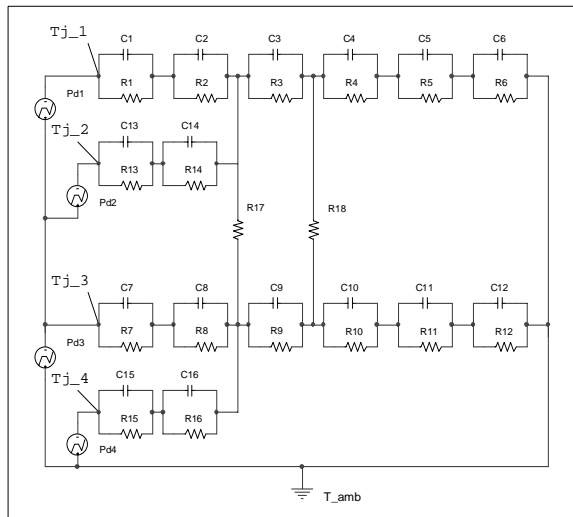
Layout condition of R_{th} and Z_{th} measurements (PCB FR4 area= 60mm x 60mm, PCB thickness=2mm, Cu thickness=35 μ m, Copper areas: 6cm²).

 $R_{thj-amb}$ Vs PCB copper area in open box free air condition

Thermal Impedance Junction Ambient Single Pulse



Thermal fitting model of a quad HSD in PowerSO-16



Pulse calculation formula

$$Z_{TH\delta} = R_{TH} \cdot \delta + Z_{THip}(1 - \delta)$$

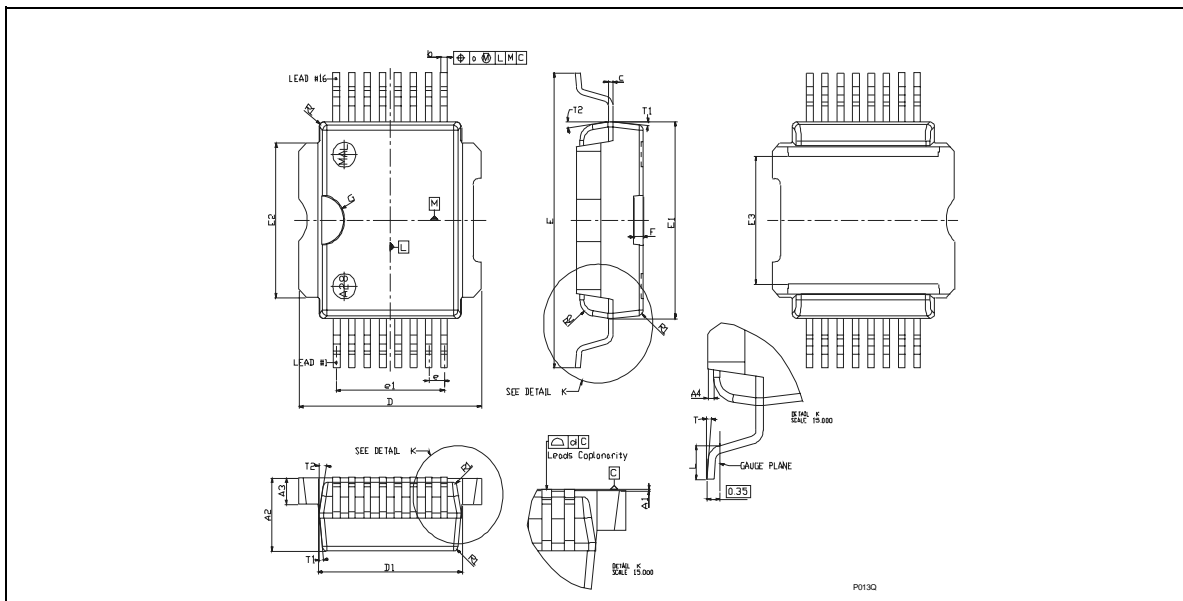
where $\delta = t_p / T$

Thermal Parameter

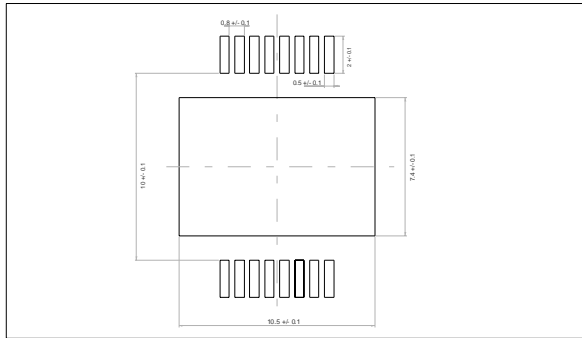
| Area/island (cm ²) | Footprint | 6 |
|--------------------------------|-----------|----|
| R1 (°C/W) | 0.18 | |
| R2 (°C/W) | 0.8 | |
| R3 (°C/W) | 0.7 | |
| R4 (°C/W) | 0.8 | |
| R5 (°C/W) | 13 | |
| R6 (°C/W) | 37 | 22 |
| C1 (W.s/°C) | 0.0006 | |
| C2 (W.s/°C) | 1.50E-03 | |
| C3 (W.s/°C) | 1.75E-02 | |
| C4 (W.s/°C) | 0.4 | |
| C5 (W.s/°C) | 0.75 | |
| C6 (W.s/°C) | 3 | 5 |

POWERSO-16™ MECHANICAL DATA

| DIM. | mm. | | |
|----------------|-------|------------|-------|
| | MIN. | TYP | MAX. |
| A1 | 0 | 0.05 | 1 |
| A2 | 3.4 | 3.5 | 3.6 |
| A3 | 1.2 | 1.3 | 1.4 |
| A4 | 0.15 | 0.2 | 0.25 |
| a | | 0.2 | |
| b | 0.27 | 0.35 | 0.43 |
| c | 0.23 | 0.27 | 0.32 |
| D | 9.4 | 9.5 | 9.6 |
| D1 | 7.4 | 7.5 | 7.6 |
| d | 0 | 0.05 | 0.1 |
| E (1) | 13.85 | 14.1 | 14.35 |
| E1 | 9.3 | 9.4 | 9.5 |
| E2 | 7.3 | 7.4 | 7.5 |
| E3 | 5.9 | 6.1 | 6.3 |
| e | | 0.8 | |
| e1 | | 5.6 | |
| F | | 0.5 | |
| G | | 1.2 | |
| L | 0.8 | 1 | 1.1 |
| R1 | | | 0.25 |
| R2 | | 0.8 | |
| T | 2° | 5° | 8° |
| T1 | | 6° (typ.) | |
| T2 | | 10° (typ.) | |
| Package Weight | | (typ.) | |



PowerSO-16™ SUGGESTED PAD LAYOUT



TUBE SHIPMENT (no suffix)

All dimensions are in mm.

| Base Q.ty | Bulk Q.ty | Tube length (± 0.5) | A | B | C (± 0.1) |
|-----------|-----------|---------------------|-----|------|-----------|
| 50 | 1000 | 532 | 4.9 | 17.2 | 0.8 |

TAPE AND REEL SHIPMENT (suffix “13TR”)

40mm min. Access hole at slot location

Full radius

Tape slot in core for tape start 2.5mm min. width.

G measured at hub

REEL DIMENSIONS

| | |
|---------------|------|
| Base Q.ty | 600 |
| Bulk Q.ty | 600 |
| A (max) | 330 |
| B (min) | 1.5 |
| C (± 0.2) | 13 |
| F | 20.2 |
| G (+ 2 / - 0) | 24.4 |
| N (min) | 60 |
| T (max) | 30.4 |

All dimensions are in mm.

TAPE DIMENSIONS
According to Electronic Industries Association (EIA) Standard 481 rev. A, Feb. 1986

| | | |
|-------------------|--------------|------|
| Tape width | W | 24 |
| Tape Hole Spacing | P0 (± 0.1) | 4 |
| Component Spacing | P | 24 |
| Hole Diameter | D (± 0.1/-0) | 1.5 |
| Hole Diameter | D1 (min) | 1.5 |
| Hole Position | F (± 0.05) | 11.5 |
| Compartment Depth | K (max) | 6.5 |
| Hole Spacing | P1 (± 0.1) | 2 |

TOP COVER TAPE

User Direction of Feed

End

Start

No components

Components

No components

500mm min

Empty components pockets sealed with cover tape.

500mm min

User direction of feed

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